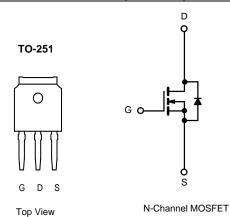


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N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}$ (Ω)	I _D (A) ^{a, e}	Q _g (Typ)		
30	0.0031 at V _{GS} = 10 V	80	82 nC		
30	0.0051 at V _{GS} = 4.5 V	80	02 110		



FEATURES

- **DT-Trench Power MOSFET**
- 100 % R_g and UIS Tested
 Compliant to RoHS Directive 2011/65/EU



APPLICATIONS

- OR-ing
- Server
- DC/DC

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		V _{DS}	30	V	
Gate-Source Voltage		V _{GS}	± 20	¬	
	T _C = 25 °C		80 ^{a, e}		
Continuous Drain Current (T _{.I} = 175 °C)	T _C = 70 °C	L	80 ^e	A	
Continuous Diam Curient (1 _J = 175°C)	T _A = 25 °C	I _D	28.8 ^{b, c}		
	T _A = 70 °C		27 ^{b, c}		
Pulsed Drain Current		I _{DM}	240		
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	36		
Single Pulse Avalanche Energy	L = 0.1 IIII	E _{AS}	64.8	V	
Continuous Source-Drain Diode Current	T _C = 25 °C	l _a	80 ^{a, e}	Α Α	
Continuous Source-Diam Diode Current	T _A = 25 °C	I _S	3.13 ^{b, c}		
	T _C = 25 °C		200 ^a	w	
Maximum Power Dissipation	T _C = 70 °C	P _D	125		
Maximum Power Dissipation	T _A = 25 °C	' D	3.75 ^{b, c}		
	T _A = 70 °C		2.63 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 175	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Тур.	Max.	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 sec	R_{thJA}	32	40	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	0.5	0.6	- C/VV	

Notes:

- a. Based on T_C = 25 °C.
 b. Surface mounted on 1" x 1" FR4 board.

- b. Surface mounted on F. A. F. F. Scale.

 c. t = 10 sec.

 d. Maximum under steady state conditions is 90 °C/W.

 e. Calculated based on maximum junction temperature. Package limitation current is 90 A.



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Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	<u>'</u>		I.				
Drain-Source Breakdown Voltage	V_{DS}	V _{GS} = 0 V, I _D = 250 μA	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	$\Delta V_{DS}/T_{J}$ $I_{D} = 250 \mu A$		35		\//90	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 230 μA		- 7.5		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1.5		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zana Oata Valla va Busin Oamani	I _{DSS}	V _{DS} = 30 V, V _{GS} = 0 V			1		
Zero Gate Voltage Drain Current		V _{DS} = 30 V, V _{GS} = 0 V, T _J = 55 °C			10	10 µA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	90			Α	
		$V_{GS} = 10 \text{ V}, I_D = 28.8 \text{ A}$		0.0024	0.0031		
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 27 \text{ A}$		0.0037	0.0054	Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 28.8 A		150		S	
Dynamic ^b			L				
Input Capacitance	C _{iss}			4612		pF	
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		725			
Reverse Transfer Capacitance	C _{rss}			570			
Total Gate Charge	Qg	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 28.8 \text{ A}$		171	257	nC	
				81.5	123		
Gate-Source Charge	Q_{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 28.8 \text{ A}$		34			
Gate-Drain Charge	Q_{gd}			29			
Gate Resistance	R _g	f = 1 MHz		1.4	2.1	Ω	
Turn-On Delay Time	t _{d(on)}			18	27		
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.625 Ω		11	17	-	
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 24$ A, $V_{GEN}=10$ V, $R_g=1$ Ω		70	105		
Fall Time	t _f			10	15		
Turn-On Delay Time	t _{d(on)}			55	83	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.67 Ω		180	270	- - -	
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 22.5 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		55	83		
Fall Time	t _f			12	18		
Drain-Source Body Diode Characteristic	s		L				
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			80	۸	
Pulse Diode Forward Current ^a	I _{SM}				240	A	
Body Diode Voltage	V_{SD}	I _S = 22 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			52	78	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	1 20 A di/dt 100 A/va T 25 °C		70.2	105	nC	
Reverse Recovery Fall Time	t _a	$I_F = 20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		27			
Reverse Recovery Rise Time	t _b	7		25		ns	

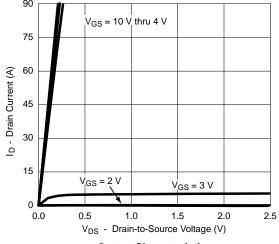
Notes:

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

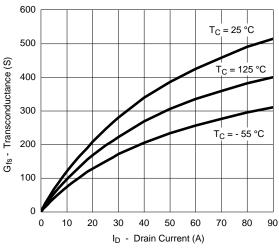
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



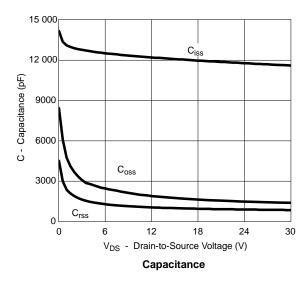
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

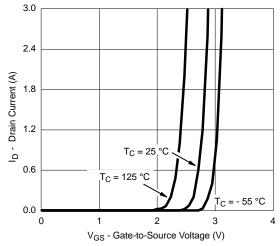




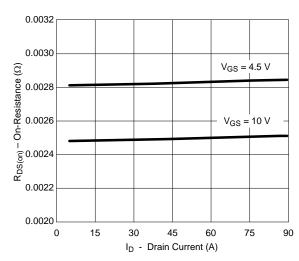


Transconductance

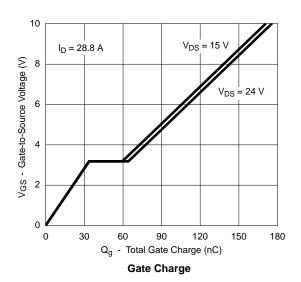




Transfer Characteristics

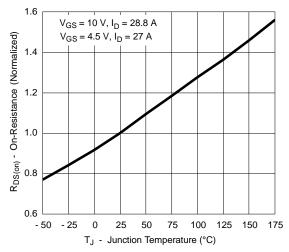


R_{DS(on)} vs. Drain Current

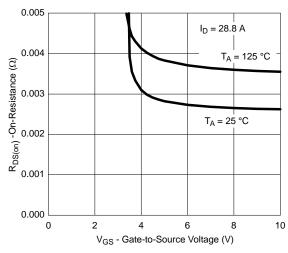




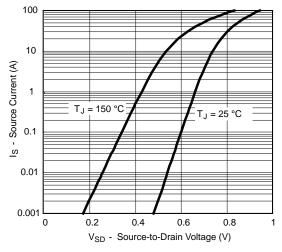
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



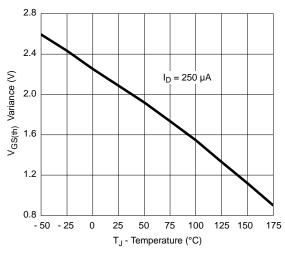
On-Resistance vs. Junction Temperature



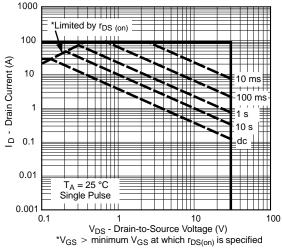
 $R_{DS(on)}$ vs. V_{GS} vs. Temperature



Forward Diode Voltage vs. Temperature



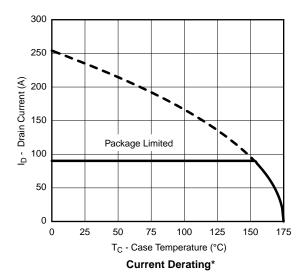
Threshold Voltage

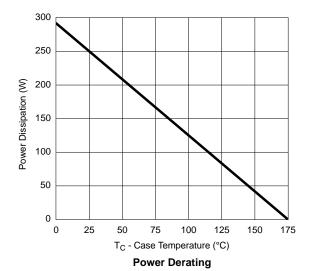


Safe Operating Area, Junction-to-Ambient

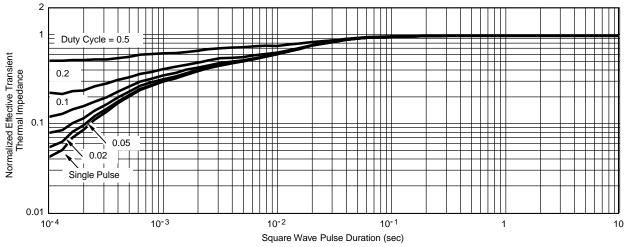


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





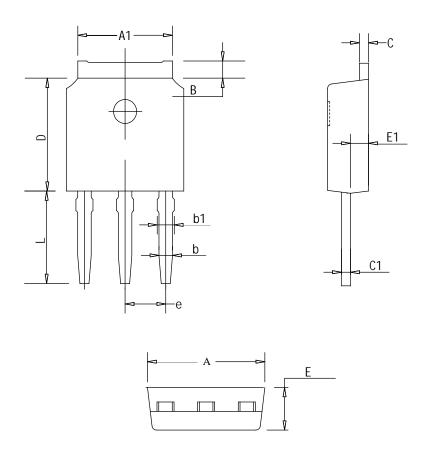
*The power dissipation P_D is based on $T_{J(max)}$ = 175 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



Normalized Thermal Transient Impedance, Junction-to-Case



TO-251 PACKAGE OUTLINE



COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	TYP	MAX
Α	6.30	6.60	6.90
A1	5.00	5.30	5.60
В	0.80	1.00	1.20
С	0.40	0.50	0.60
C1	0.40	0.50	0.60
D	5.80	6.10	6.40
Е	2.10	2.30	2.50
E1	0.80	1.00	1.20
L	4.50	5.00	5.50
е	2.10	2.30	2.50
b	0.66	0.76	0.86
b1	0.66	0.86	1.06





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